

Inventors: William H. Howland, Jr. and Christine E. Kalnas
 "METHOD AND APPARATUS FOR DETERMINING THE DIELECTRIC CONSTANT OF A LOW
 PERMITTIVITY DIELECTRIC ON A SEMICONDUCTOR WAFER"

Attorney Docket No.: 1880-031569

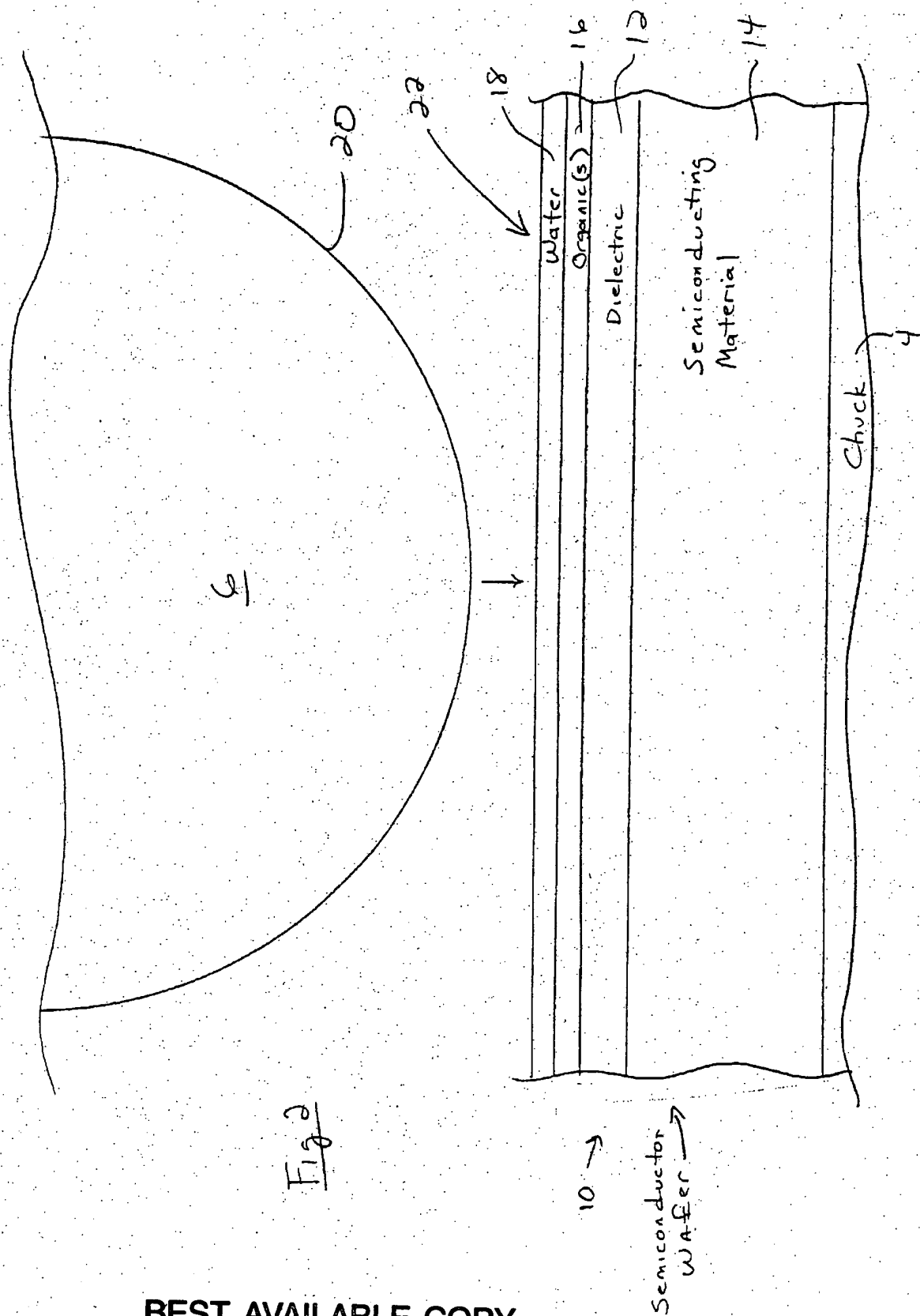


Fig. 2

BEST AVAILABLE COPY

Fig 3

Inventors: William H. Howland, Jr. and Christine E. Kalnas
"METHOD AND APPARATUS FOR DETERMINING THE DIELECTRIC CONSTANT OF A LOW PERMITTIVITY DIELECTRIC ON A SEMICONDUCTOR WAFER"
Attorney: Doaklet No. 1880-031569

1127

BEST AVAILABLE COPY